

#### **Feature**

- High Precision GaAs process
- High performance, shielded
- ullet GaAs substrate,  $50\Omega$  CPW output
- Au wire bonding, for MCM applications

## **Environmental Specifications**

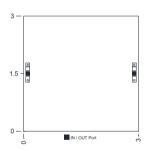
Operating Temperature	-55℃~+85℃	
Storage Temperature	-65°C∼+150°C	
Max. Input Power	30dBm	

# Electrical Specifications(T<sub>A</sub>=+25°C)

Parameter	Min.	Тур.	Max.	Unit
Center Freq. (f₀)	=	10.25	-	GHz
Pass band	10	ı	10.5	GHz
Insertion Loss @ f <sub>0</sub>	=	ı	2.5	dB
Ripple in Pass band	-	-	1	dB
Return Loss	10	-	-	dB
Out of band	≥40@9.15GHz			dB
Attenuation	≥30@12.6GHz			dB

S2P file name: BWBF-10\_10R5.s2p

# **Outline Drawing**



#### Notes:

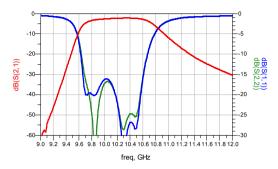
- 1. Dimensions are in millimeters. Tolerance: ±0.05mm
- 2. Die thickness is 0.1mm
- 3. Typical bond pad is 0.1x0.1 mm<sup>2</sup>.
- 4. The bottom of the device is gold plated, should be grounded.

### **Typical Test Curves**

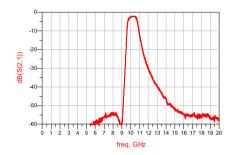
Insertion Loss VS Frequency (T<sub>A</sub>=25°C)



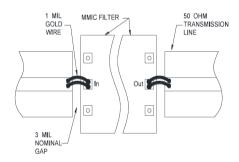
Insertion Loss & Return Loss VS Frequency (T<sub>A</sub>=25°C)



Broadband Insertion Loss VS Frequency (T<sub>A</sub>=25°C)



### **Recommended Assembly Diagrams**



## **Application Notes:**

- 1. The chip is back-metallized and can be die-mounted with AuSn eutectic preforms or with electrically conductive epoxy.
- 2. The die should be assembled on carriers like Kovar or Mu-Cu which have same Coefficient of thermal expansion. (5.8×10-6/) with GaAs.
- 3. Recommend using  $\Phi$ 25um Au wire for bonding, whose length is around 400um.
- 4. Sinter by AuSn (80/20), which doesn't exceed 300°C within 30 seconds max.
- 4. Handle the chips in a clean environment. DO NOT attempt to clean the chip using liquid cleaning systems.
- 5. Handle the chip along the edges with a vacuum collet or with a sharp pair of bent tweezers.
- 6. The device is sensitive to ESD. ESD protection is required during storage and usage.
- 7. If you have any questions, please contact us.